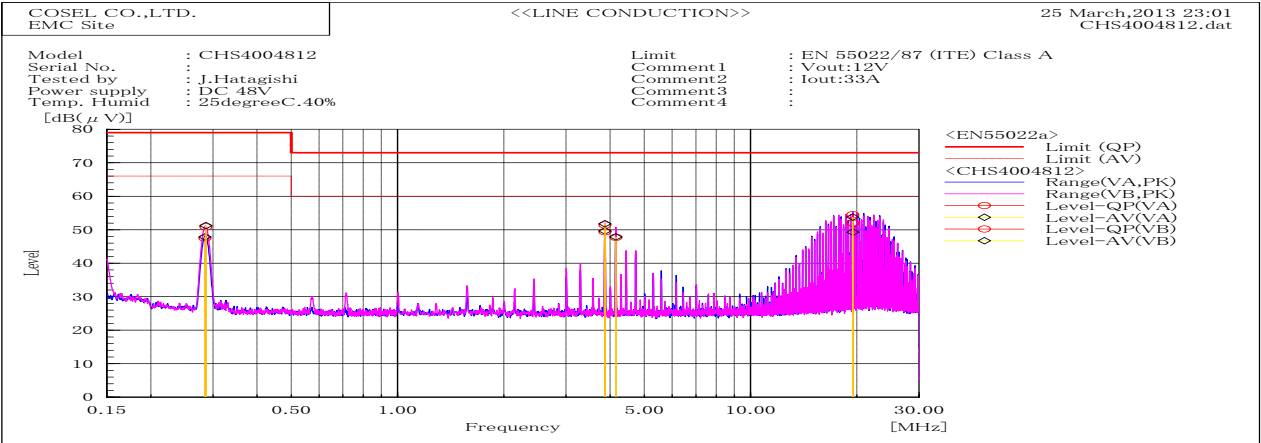
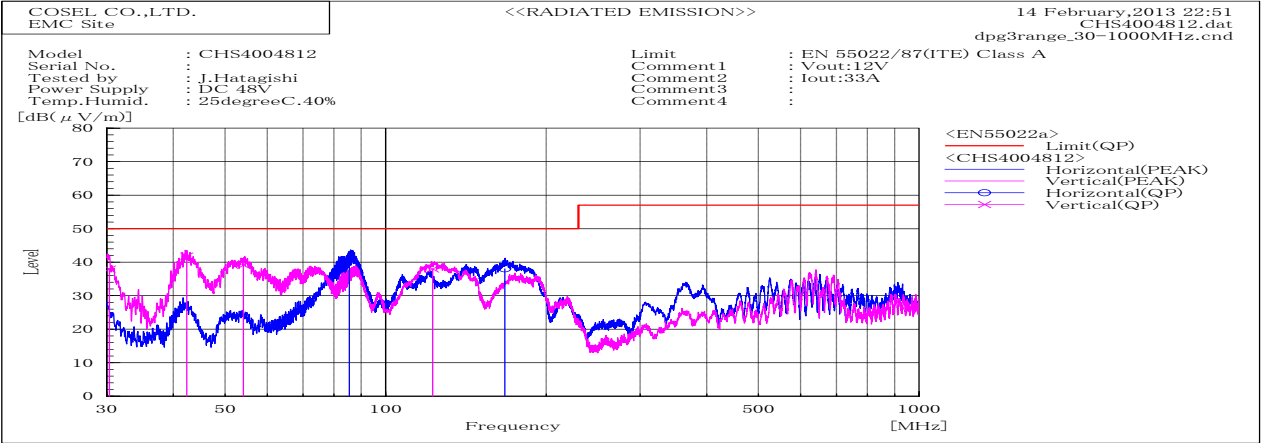


DATA SHEET		Date	26-Mar-13
Model	CHS4004812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi



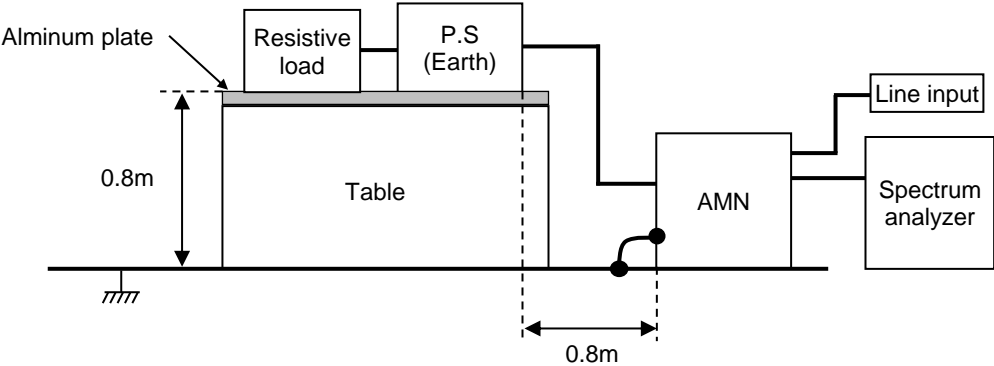
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.28492		VA	27.5	27.8	20	47.5	47.8	79	66	31.5	18.2	Pass	
0.2866		VB	30.8	31.2	20	50.8	51.2	79	66	28.2	14.8	Pass	
3.87028		VA	29.2	29.4	20.2	49.4	49.6	73	60	23.6	10.4	Pass	
3.86848		VB	31.2	31.6	20.2	51.4	51.8	73	60	21.6	8.2	Pass	
4.15644		VA	27.5	27.6	20.2	47.7	47.8	73	60	25.3	12.2	Pass	
19.49265		VA	30.9	28.3	21	51.9	49.3	73	60	21.1	10.7	Pass	
19.4847		VB	33.6	32.9	20.9	54.5	53.8	73	60	18.5	6.2	Pass	



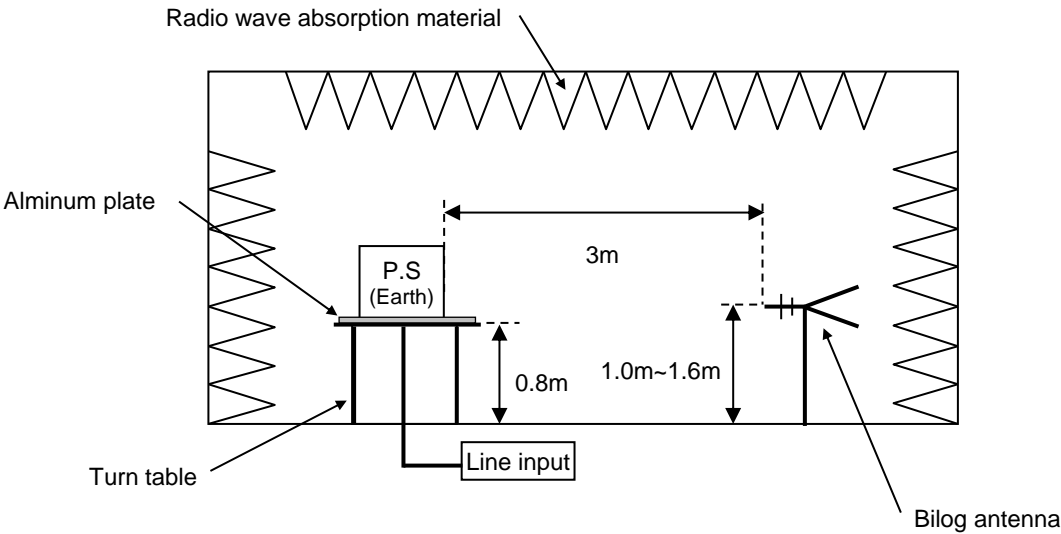
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.347	V	Stable	51.4		-13.5	37.9		50	12.1	Pass	102	249	
42.366	V	Stable	58.5		-16.7	41.8		50	8.2	Pass	106	6	
54.095	V	Stable	63.1		-24	39.1		50	10.9	Pass	106	63	
85.477	H	Stable	63.1		-22.3	40.8		50	9.2	Pass	155	56	
122.529	V	Stable	55.1		-17.1	38		50	12	Pass	121	316	
167.225	H	Stable	60		-22	38		50	12	Pass	151	50	

DATA SHEET		Date	26-Mar-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi

1. Line conduction



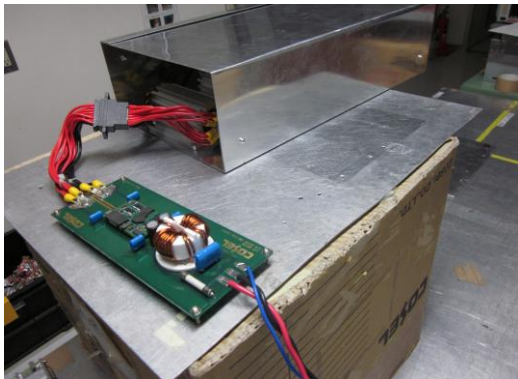
2. Radiated emission



Test: EMI
Model Name:CHS40048□

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

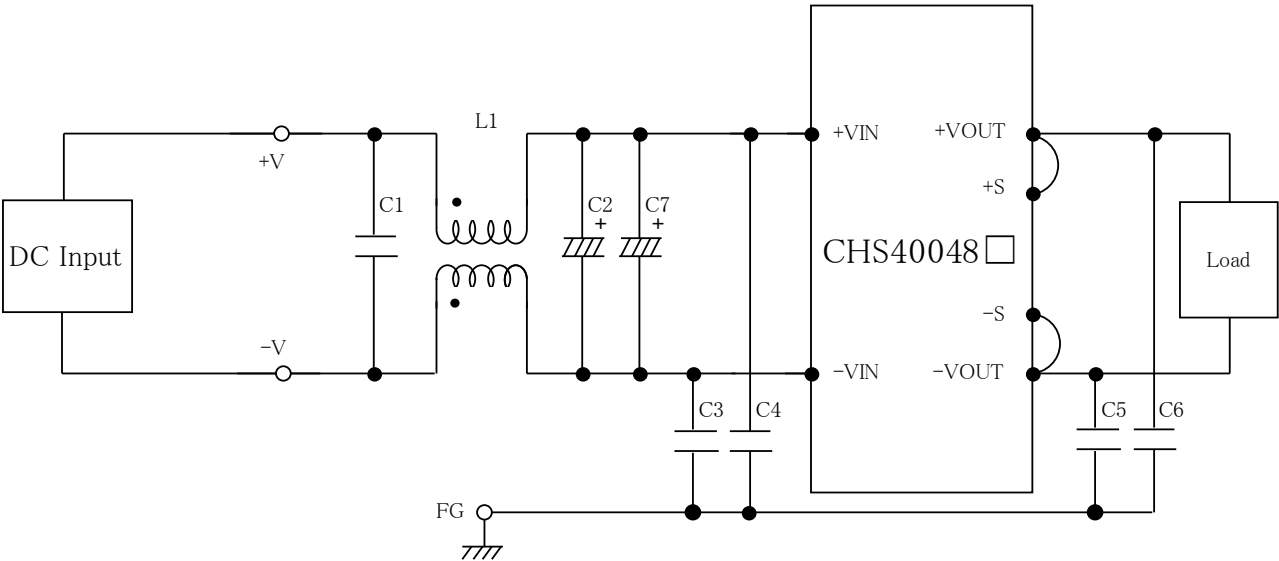


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C7 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)